

# **Chlorinated compounds in ethylene** Analysis of impurities in ethylene

# **Application Note**

Materials Testing & Research

### Authors

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### Introduction

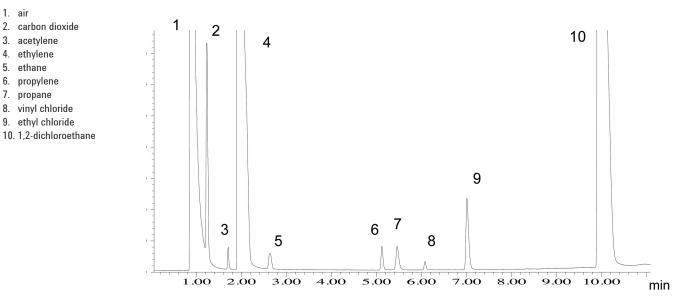
GC/MS analysis of chlorinated impurities in ethylene is achieved in 10 minutes with an Agilent CarboBOND column.



## Conditions

Technique	: GC
Column	: Agilent CarboBOND, 0.53 mm x 25 m fused silica (df = 10 μm) (Part no. CP7374) connected with 0.1 mm x 20 cm methyl deactivated fused silica at inlet
Temperature	: 80 °C (1 min) $\rightarrow$ 300 °C, 25 °C/min
Carrier Gas	: Helium, 20 kPa
Injector	: Split, 10:1
Detector	: MS
Sample Size	: 0.5 mL
Concentration range	: ethylene standard with approx. 100 ppm impurities
Concentration range	: air & ethylene

### **Peak identification**



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